

<b>FORM PTO-1449</b>		<b>DOCKET NO:</b> 60919 (70551)		<b>SERIAL NO.:</b> 10/789,085			
<b>INFORMATION DISCLOSURE STATEMENT</b>		<b>APPLICANT(S):</b> Tetsuya INUI, et al.					
		<b>FILING DATE:</b> February 27, 2004		<b>GROUP NO.:</b> Not Yet Assigned			
<b>UNITED STATES PATENT DOCUMENTS</b>							
<b>EXAM. INITIALS</b>		<b>DOCUMENT NUMBER</b>	<b>DATE</b>	<b>NAME</b>	<b>CLASS</b>	<b>SUBCLASS</b>	<b>FILING DATE IF APPROPRIATE</b>
<b>FOREIGN PATENT DOCUMENTS</b>							
		<b>DOCUMENT NUMBER</b>	<b>DATE</b>	<b>COUNTRY</b>	<b>CLASS</b>	<b>SUBCLASS</b>	<b>TRANSLATION YES/NO</b>
M)	BA	11-307450	11/05/99	JAPAN	H01L	21/20	ABSTRACT
M)	BB	58-201326	11/24/83	JAPAN	H01L	21/26	ABSTRACT
M)	BC	WO 97/45827	12/04/97	PCT	G09G	3/36	YES
<b>OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)</b>							
M)	CA	Akito Hara, et al., "Nucleus Formation Site of Silicon on Glass and Solidification Direction Control - Aiming to Form Monocrystalline Silicon Si-TFT" Textbook of the 112 <sup>th</sup> workshop of Division of Materials Science and Crystal Technology of the Japan Society of Applied Physics, Division of Materials Science and Crystal Technology of the Japan Society of Applied Physics, pp. 19-25 (2000).					
<b>EXAMINER:</b>				<b>DATE:</b>			
M. J.				3/16/06			



## REPLACEMENT 1449 FORM

<b>FORM PTO-1449</b>  <b>INFORMATION DISCLOSURE</b> <b>STATEMENT</b>	<b>DOCKET NO:</b> 60919 (70551)	<b>SERIAL NO.:</b> 10/789,085
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### UNITED STATES PATENT DOCUMENTS

EXAM. INITIALS		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

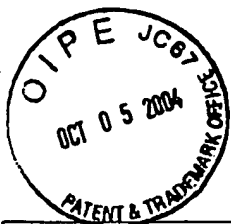
### FOREIGN PATENT DOCUMENTS

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M)	BA	11-307450	11/05/99	JAPAN	H01L	21/20	ABSTRACT
M)	BB	58-201326	11/24/83	JAPAN	H01L	21/26	ABSTRACT
M)	BC	2000-505241	04/25/00	JAPAN	H01L	21/20	NO

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<b>EXAMINER:</b> 	<b>DATE:</b> 3/16/2006
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**UNITED STATES PATENT DOCUMENTS**

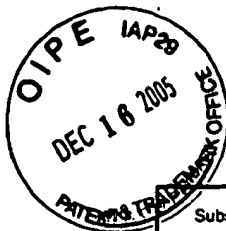
EXAM. INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

**FOREIGN PATENT DOCUMENTS**

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO
(h)	BA WO 97/45827	12/04/97	PCT	G09G	3/36	YES

**OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)**


<b>EXAMINER:</b> <i>Math J</i>	<b>DATE:</b> <i>3/16/2006</i>
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PTO/SB/08a/b (07-05)  
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Substitute for form 1449A/B/PTO  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use as many sheets as necessary)				<b>Complete if Known</b>	
				Application Number	10/789,085-Conf. #7533
				Filing Date	February 27, 2004
				First Named Inventor	Tetsuya Inui
				Art Unit	1722
				Examiner Name	M. A. Anderson
Sheet	1	of	1	Attorney Docket Number	60919(70551)

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
YVS	AA*	US-6,451,631-B1	09-17-2002	Grigoropoulos et al.	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>
MS	BA	KR-2002-14704	02-25-2002			
MS	BB	JP-08-293466	11-05-1996			✓

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. \* CITE NO.: Those application(s) which are marked with an single asterisk (\*) next to the Cite No. are not supplied (under 37 CFR 1.98(a)(2)(iii)) because that application was filed after June 30, 2003 or is available in the IFW. <sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> See Kinds Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> Applicant is to place a check mark here if English language Translation is attached.

Examiner Signature	<i>MAA</i>	Date Considered	3/16/2006
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